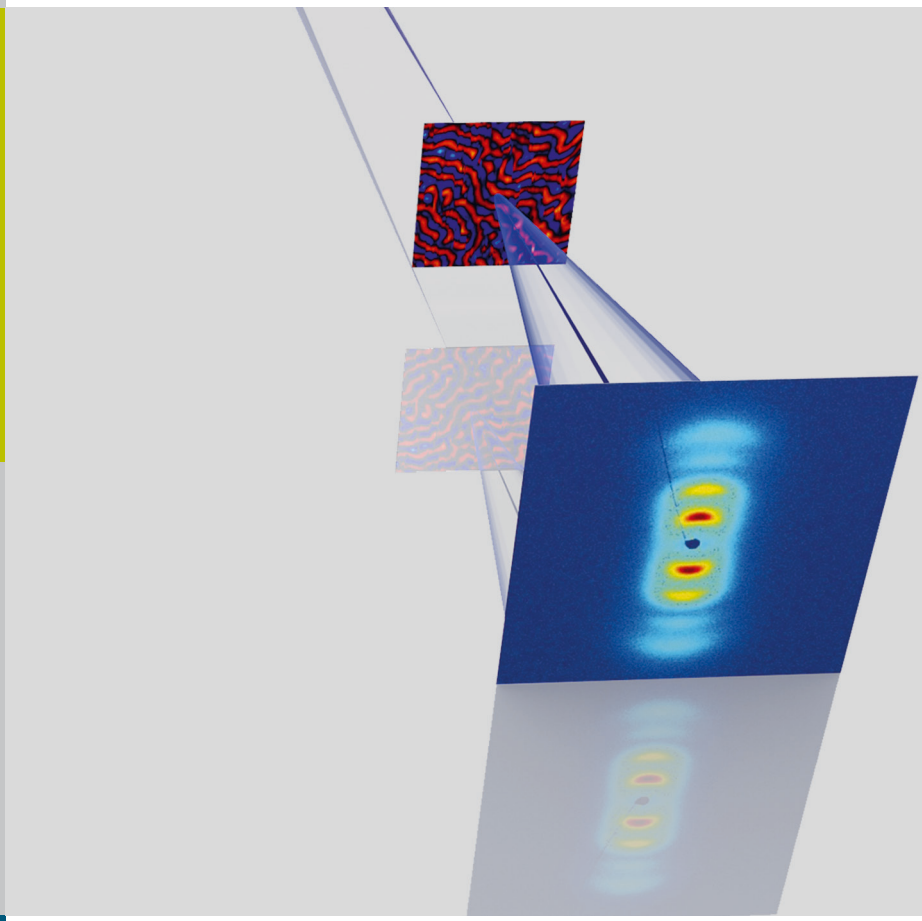
Resonant Magnetic Scattering Studies using Synchrotron Radiation and Laser-Generated Extreme Ultraviolet Light

Christian Michael Weier



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